

MOS FIELD EFFECT TRANSISTOR

μ PA1740TP

SWITCHING

N-CHANNEL POWER MOS FET

DESCRIPTION

The μ PA1740TP is N-channel MOS FET device that features a low on-state resistance and excellent switching characteristics, and designed for high voltage applications such as DC/DC converter.

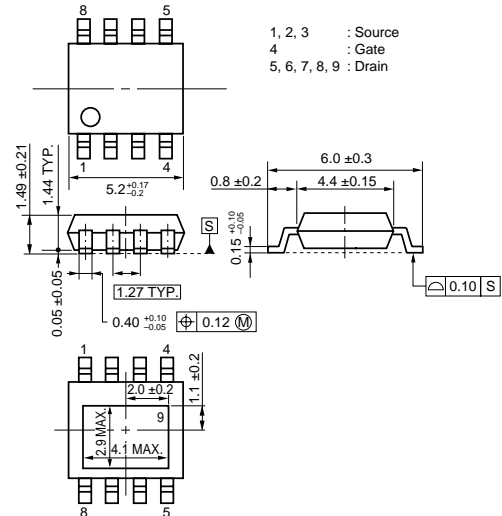
FEATURES

- High voltage: $V_{DSS} = 200$ V
- Gate voltage rating: ± 30 V
- Low on-state resistance
 $R_{DS(on)} = 0.44 \Omega$ MAX. ($V_{GS} = 10$ V, $I_D = 3.5$ A)
- Low input capacitance
 $C_{iss} = 420$ pF TYP. ($V_{DS} = 10$ V, $V_{GS} = 0$ V)
- Built-in gate protection diode
- Small and surface mount package (Power HSOP8)
- Avalanche capability rated

ORDERING INFORMATION

PART NUMBER	PACKAGE
μ PA1740TP	Power HSOP8

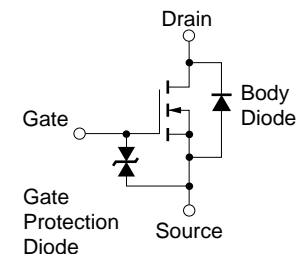
PACKAGE DRAWING (Unit: mm)



ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$, Unless otherwise noted, All terminals are connected.)

Drain to Source Voltage ($V_{GS} = 0$ V)	V_{DSS}	200	V
Gate to Source Voltage ($V_{DS} = 0$ V)	V_{GSS}	± 30	V
Drain Current (DC) ($T_C = 25^\circ\text{C}$)	$I_{D(DC)}$	± 7.0	A
Drain Current (pulse) ^{Note1}	$I_{D(pulse)}$	± 21	A
Total Power Dissipation ($T_C = 25^\circ\text{C}$)	P_{T1}	22	W
Total Power Dissipation ($T_A = 25^\circ\text{C}$) ^{Note2}	P_{T2}	1.0	W
Channel Temperature	T_{ch}	150	$^\circ\text{C}$
Storage Temperature	T_{stg}	-55 to $+150$	$^\circ\text{C}$
Single Avalanche Current ^{Note3}	I_{AS}	7.0	A
Single Avalanche Energy ^{Note3}	E_{AS}	4.9	mJ
Repetitive Avalanche Current ^{Note4}	I_{AR}	7.0	A
Repetitive Avalanche Energy ^{Note4}	E_{AR}	2.2	mJ

EQUIVALENT CIRCUIT



Notes 1. $PW \leq 10 \mu\text{s}$, Duty Cycle $\leq 1\%$

2. Mounted on a glass epoxy board (1 inch x 1 inch x 0.8 mm), $PW = 10$ sec

3. Starting $T_{ch} = 25^\circ\text{C}$, $V_{DD} = 100$ V, $R_G = 25 \Omega$, $L = 100 \mu\text{H}$, $V_{GS} = 20 \rightarrow 0$ V

4. $T_{ch} \leq 125^\circ\text{C}$, $V_{DD} = 100$ V, $R_G = 25 \Omega$

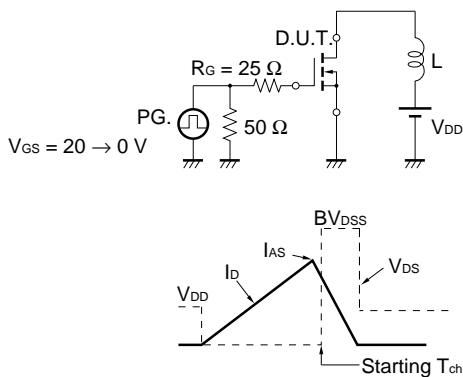
Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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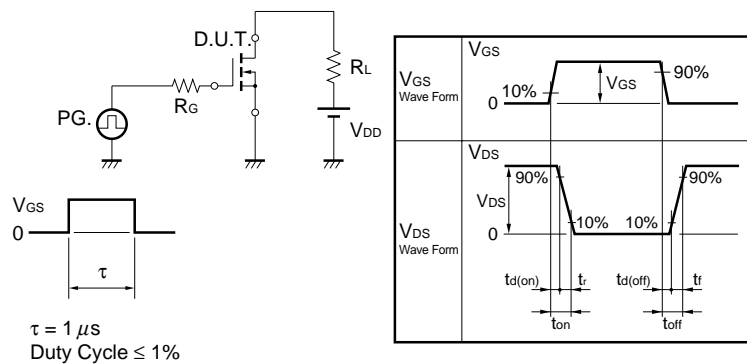
ELECTRICAL CHARACTERISTICS (T_A = 25°C, Unless otherwise noted, All terminals are connected.)

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 200 V, V _{GS} = 0 V			10	μA
Gate Leakage Current	I _{GSS}	V _{GS} = ±30 V, V _{DS} = 0 V			±10	μA
Gate Cut-off Voltage	V _{GS(off)}	V _{DS} = 10 V, I _D = 1.0 mA	2.5	3.5	4.5	V
Forward Transfer Admittance	y _{fs}	V _{DS} = 10 V, I _D = 3.5 A	3	4.5		S
Drain to Source On-state Resistance	R _{DS(on)}	V _{GS} = 10 V, I _D = 3.5 A		0.35	0.44	Ω
Input Capacitance	C _{iss}	V _{DS} = 10 V		420		pF
Output Capacitance	C _{oss}	V _{GS} = 0 V		100		pF
Reverse Transfer Capacitance	C _{rss}	f = 1 MHz		45		pF
Turn-on Delay Time	t _{d(on)}	V _{DD} = 100 V, I _D = 3.5 A		5		ns
Rise Time	t _r	V _{GS} = 10 V		7.5		ns
Turn-off Delay Time	t _{d(off)}	R _G = 10 Ω		21		ns
Fall Time	t _f			7		ns
Total Gate Charge	Q _G	V _{DD} = 160 V		12		nC
Gate to Source Charge	Q _{GS}	V _{GS} = 10 V		2		nC
Gate to Drain Charge	Q _{GD}	I _D = 7.0 A		6.5		nC
Body Diode Forward Voltage	V _{F(S-D)}	I _F = 7.0 A, V _{GS} = 0 V		1.0	1.5	V
Reverse Recovery Time	t _{rr}	I _F = 7.0 A, V _{GS} = 0 V		110		ns
Reverse Recovery Charge	Q _{rr}	di/dt = 50 A/μs		360		nC

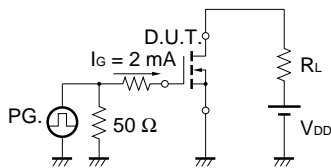
TEST CIRCUIT 1 AVALANCHE CAPABILITY



TEST CIRCUIT 2 SWITCHING TIME

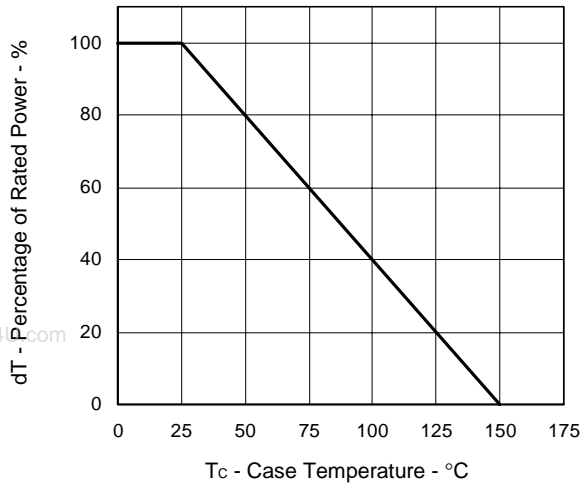


TEST CIRCUIT 3 GATE CHARGE

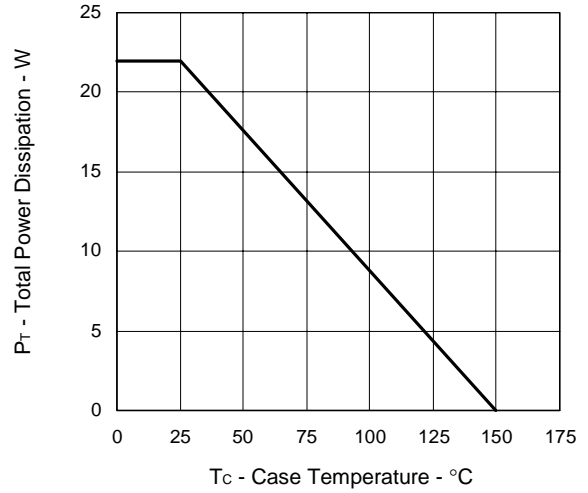


TYPICAL CHARACTERISTICS (T_A = 25°C)

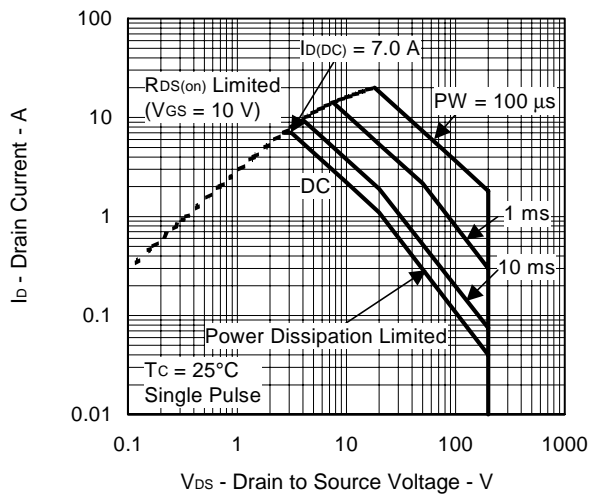
DERATING FACTOR OF FORWARD BIAS SAFE OPERATING AREA



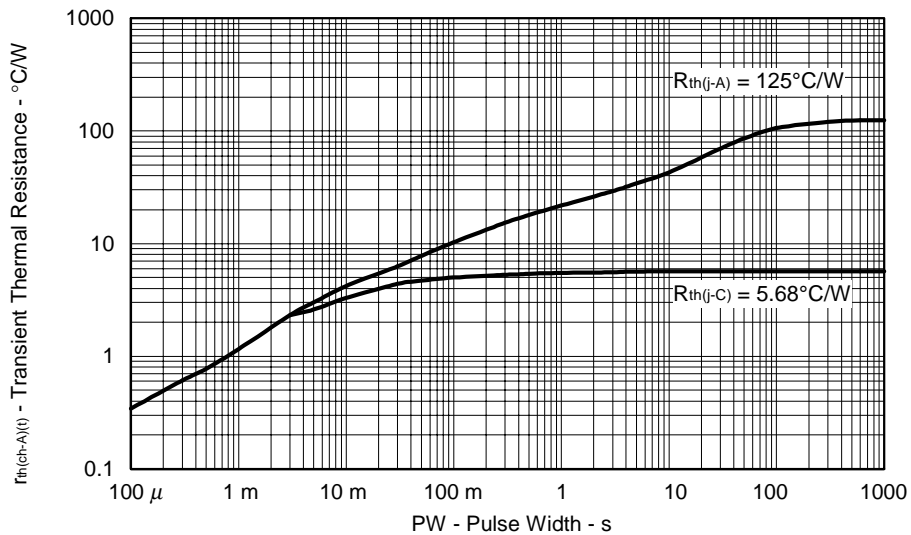
TOTAL POWER DISSIPATION vs. CASE TEMPERATURE



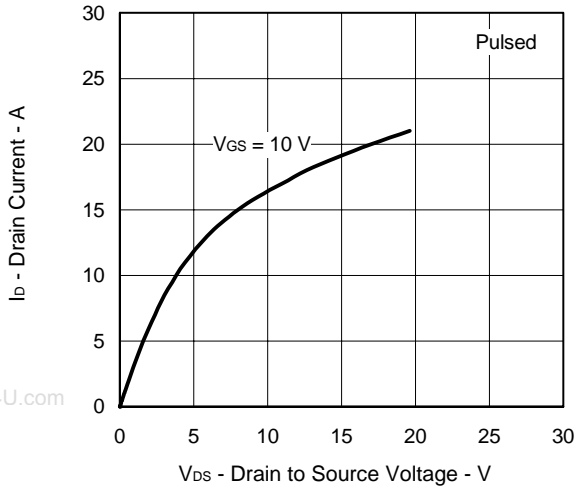
FORWARD BIAS SAFE OPERATING AREA



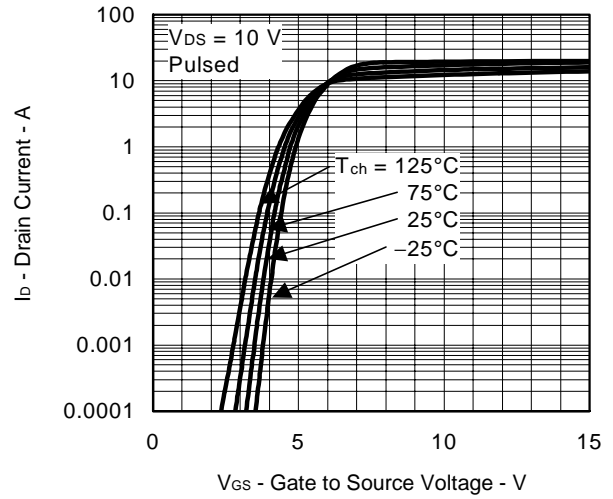
TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



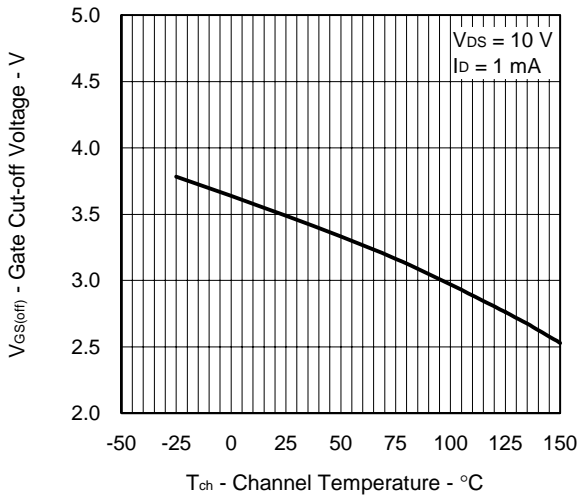
DRAIN CURRENT vs. DRAIN TO SOURCE VOLTAGE



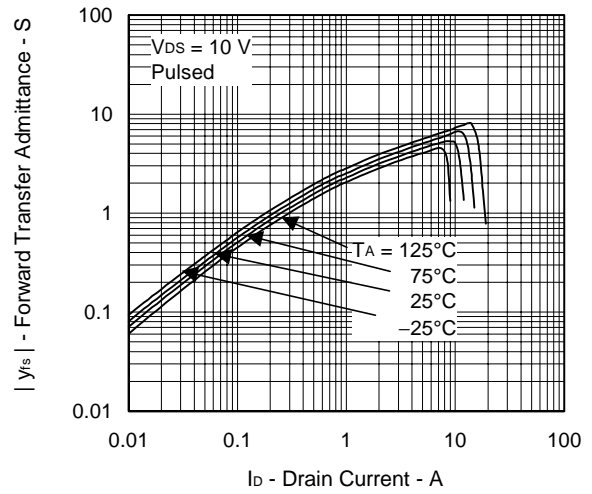
FORWARD TRANSFER CHARACTERISTICS



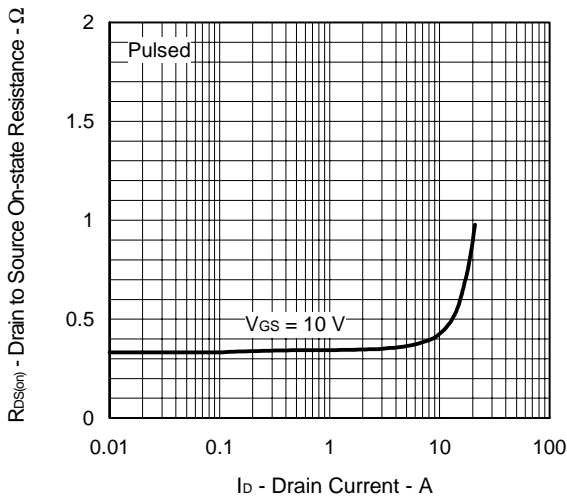
GATE CUT-OFF VOLTAGE vs. CHANNEL TEMPERATURE



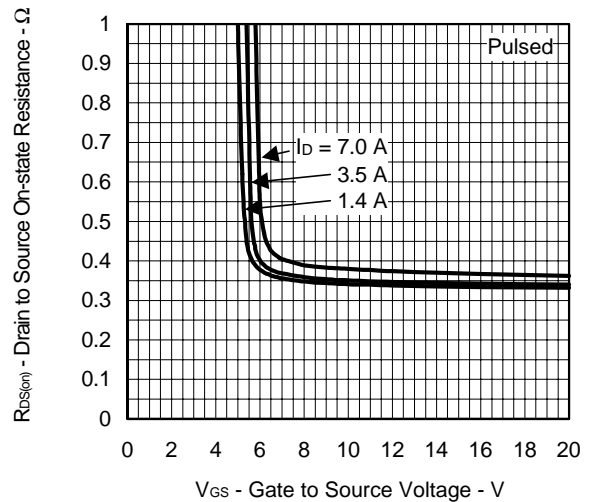
FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT



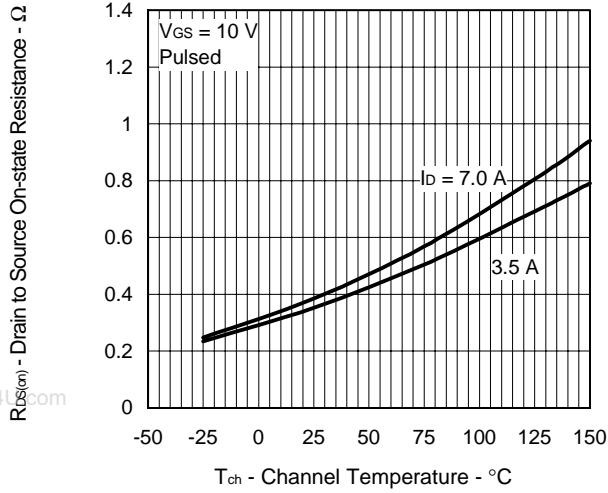
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



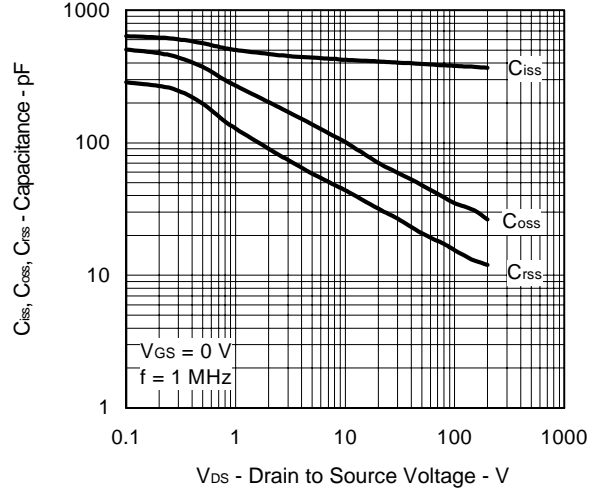
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



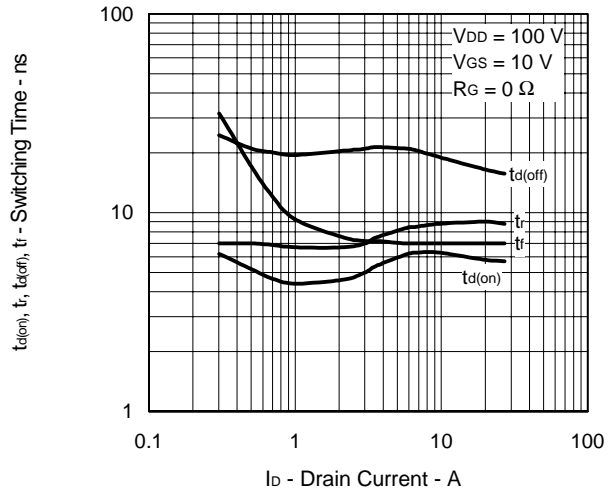
DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



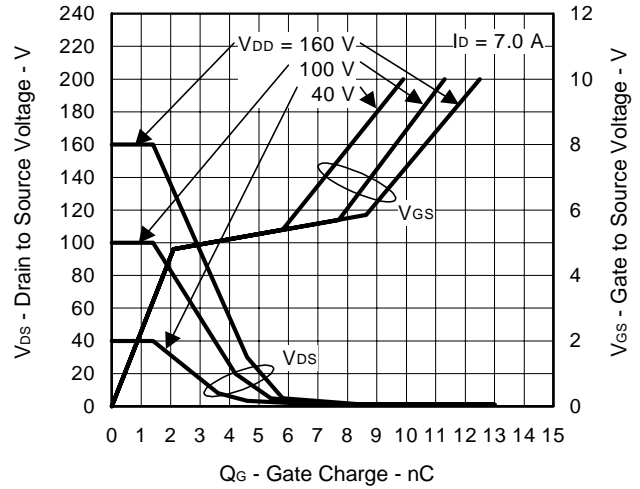
CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



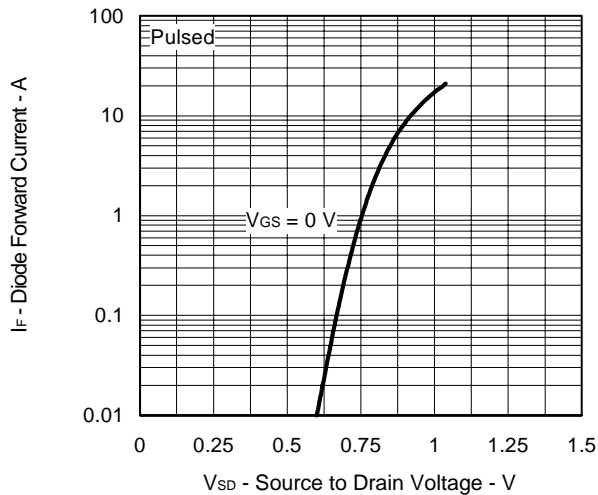
SWITCHING CHARACTERISTICS



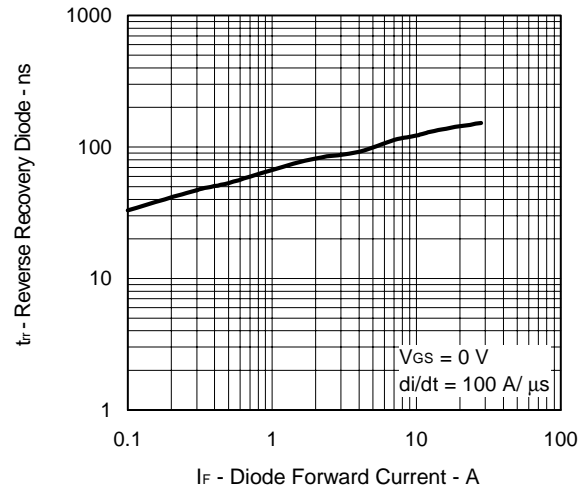
DYNAMIC INPUT/OUTPUT CHARACTERISTICS



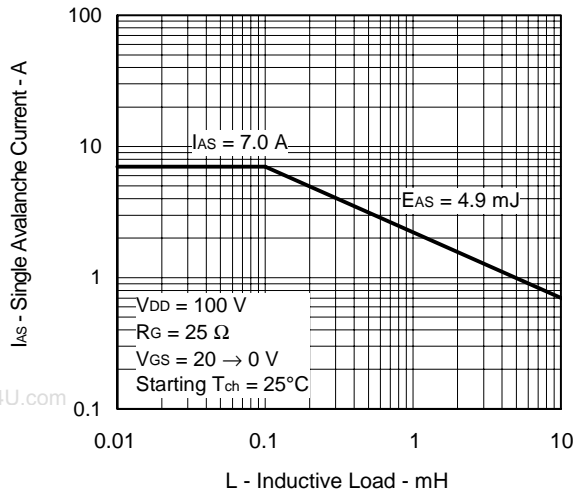
SOURCE TO DRAIN DIODE FORWARD VOLTAGE



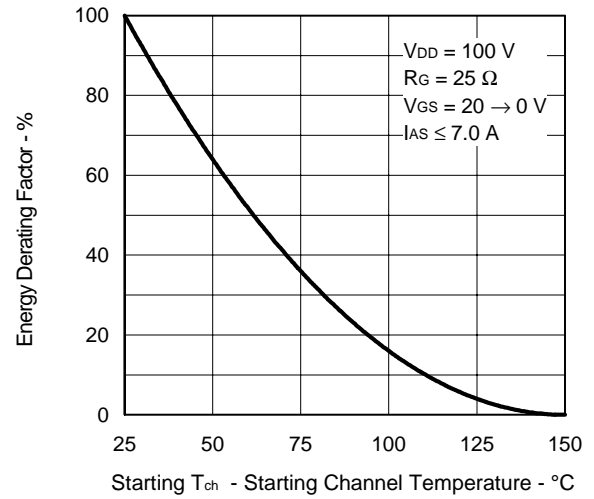
REVERSE RECOVERY TIME vs. DIODE FORWARD CURRENT



SINGLE AVALANCHE CURRENT vs. INDUCTIVE LOAD



SINGLE AVALANCHE ENERGY DERATING FACTOR



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